

FORM PTO-1449 (MODIFIED)

ATTORNEY DOCKET NO.

SERIAL NO.

SP00-386

10/023,291

U.S. DEPT. OF PATENTS AND
PUBLICATIONS
FOR APPLICANTS INFORMATION
DISCLOSURE STATEMENT

APPLICANT Berkey et al.

FILING DATE December 14,
2001

GROUP: 2874

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date if Approp.
	AA						
	AB						
	AC						
	AD						
	AE						
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	AG						
	AH						
	AI						
	AJ						
	AK						

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FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub-Class	Translation Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							
	AQ							

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

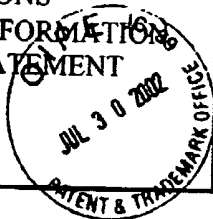
AR	Kumar et al, "Effects of Deuterium Treatments on the Optical Properties of Fused Silica", <i>Laser Induced Damage in Optical Materials: 1981</i> , pp. 268-272
AS	
AT	
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FORM PTO-1449 (MODIFIED) LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS INFORMATION DISCLOSURE STATEMENT	ATTORNEY DOCKET NO.	SERIAL NO.
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Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date if Approp.
	BN	09/558,770	/	Allen et al	—	—	04/26/00
	BO	09/722,804	/	Bookbinder et al	—	—	11/27/00
	BP	09/822,168	/	Berkey et al	—	—	03/31/01
	BQ	09/996,632	/	Berkey et al	—	—	11/28/01
	BR	10/023,291	/	Berkey et al	—	—	12/14/01
	BS	60/309,160	/	Berkey et al	—	—	07/31/02

FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Sub-Class	Translation Yes No
	BT	10-68834	✓ 03/10/98	Japan	G02B	6/16	X
	BU	55-23081	✓ 02/19/80	Japan	C03B	37/00	X
	BV	57-17433	✓ 01/29/82	Japan	C03B	37/00	X
	BW	57-34034	✓ 02/24/82	Japan	C03B	37/00	X
	BX	60-71536	✓ 04/23/85	Japan	C03B	37/018	X
	BY	60-86043	✓ 05/15/85	Japan	C03B	37/018	X
	BZ	63-225546	✓ 09/20/88	Japan	C03B	37/018	X
	CA	WO00/64824	✓ 11/02/00	PCT	C03B	37/00	
	CB	WO00/64825	✓ 11/02/00	PCT	C03B	37/014	

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)	
	CC Dianov et al, "Low-Hydrogen Silicon Oxynitride Optical Fibers Prepared by SPCVD", Journal of Lightwave Technology, July 1995, vol. 13, No. 7, pp. 1471-1474
	CD Diaz de la Iglesia et al, "Loss Spread in Single-Mode Fibers Due to OH-Ion Concentration and Transmitter-Wavelength Fluctuations", International Wire & Cable Symposium Proceedings 1987, pp. 629-639
	CE Hanawa et al, "Fabrication of Completely OH-Free V.A.D. Fibre", Electronics Letters, August 28, 1980, vol. 16, No. 18, pp. 699-700

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6-03

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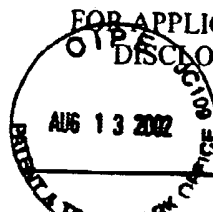
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